Unit: mm

4.2±0.2

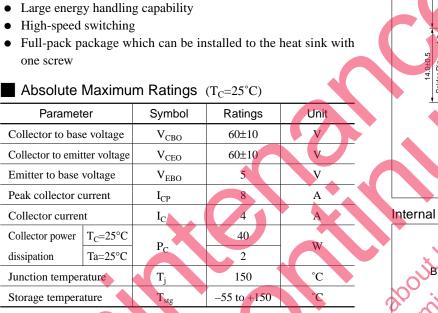
2SD1326

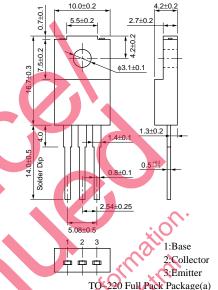
Silicon NPN triple diffusion planar type Darlington

For midium speed power switching

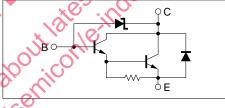
Features

- Incorporating a zener diode of 60V zener voltage between col-. lector and base
- Minimized variation in the breakdown voltage .
- High-speed switching
- one screw





Internal Connection.



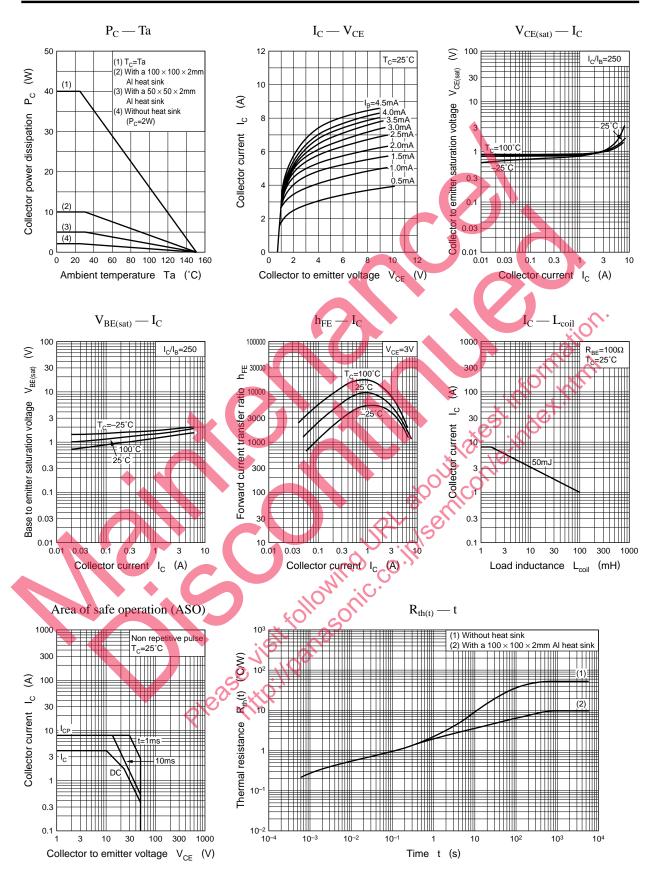
Electrical Characteristics (T_c=25°C)

						1		1
Parameter			Symbol	Conditions	min	typ	max	Unit
Collector cutoff current			I _{CBO}	$V_{\rm CB} = 50 \text{V}, I_{\rm E} \ge 0$			100	μA
Emitter cutoff current			I _{EBO}	$V_{\rm EB} = 5V, I_{\rm C} = 0$			2	mA
Collector to emitter voltage			V _{CEO}	$I_C = 5mA, I_B = 0$	50		70	V
Forward current transfer ratio			h _{FE1}	$V_{CE} = 3X$ $I_C = 0.5A$	1000			
Forward cu	rrent transfer ra		h_{FE2}^{*1}	$V_{CE} = 3V, I_C = 3A$	2000		10000	
Collector to emitter saturation voltage		1	V _{CE(sal)}	$I_{\rm C} = 3{\rm A}, I_{\rm B} = 12{\rm mA}$			2.5	v
		n voltage		$I_{\rm C} = 5$ A, $I_{\rm B} = 20$ mA			4	
Base to emitter saturation voltage V_{I}			V _{BE(sat)}	$I_{\rm C} = 3A, I_{\rm B} = 12mA$			2.5	V
Transition frequency			f _T	$V_{CE} = 10V, I_C = 0.5A, f = 1MHz$		20		MHz
Turn-on time			ton	$I_{C} = 3A, I_{B1} = 12mA, I_{B2} = -12mA,$ $V_{CC} = 50V$		0.3		μs
Storage time			t _{stg}			3		μs
Fall time			t _f			1		μs
Energy handling capability $E_{s/b}^{*2}$			E _{s/b} *2	$I_{\rm C} = 2A, L = 100 {\rm mH}, R_{\rm BE} = 100 {\Omega}$	50			mJ
^{*1} h _{FE2} Rank	classification	n		^{*2} E _{s/b} Test circuit				
Rank	Rank Q P			60Hz mercury relayOX				
h _{FE2} 2000 to 5000 4000 to 100			000					

6V

\$1Ω

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